- Digital Design Avoids Analog Compensation Errors
- . Easily Cascadable for Higher Order Loops
- Useful Frequency from DC to: 50 MHz Typical (K Clock) 35 MHz Typical (I/D Clock)

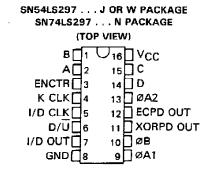
## description

The SN54LS297 and SN74LS297 devices are designed to provide a simple, cost-effective solution to high-accuracy, digital, phase-locked-loop applications. These devices contain all the necessary circuits, with the exception of the divide-by-N counter, to build first order phase-locked loops as described in Figure 1.

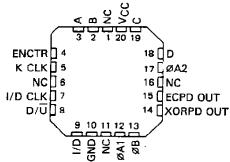
Both exclusive-OR (XORPD) and edge-controlled (ECPD) phase detectors are provided for maximum flexibility.

Proper partitioning of the loop function, with many of the building blocks external to the package, makes it easy for the designer to incorporate ripple cancellation or to cascade to higher order phase-locked loops.

The length of the up/down K counter is digitally programmable according to the K counter function table. With A, B, C, and D all low, the K counter is disabled. With A high and B, C, and D low, the K counter is only

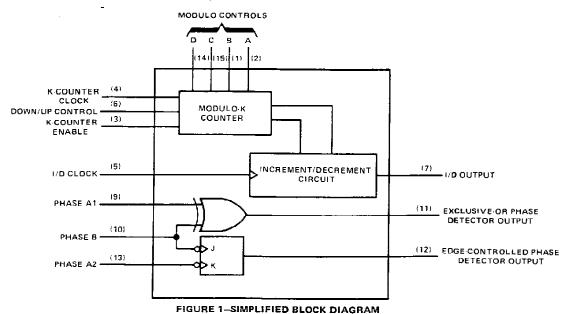


SN54LS297 . . . FK PACKAGE (TOP VIEW)



NC-No internal connection

three stages long, which widens the bandwidth or capture range and shortens the lock time of the loop. When A, B, C, and D are all programmed high, the K counter becomes seventeen stages long, which narrows the bandwidth or capture range and lengthens the lock time. Real-time control of loop bandwidth by manipulating the A through D inputs can maximize the overall performance of the digital phase-locked loop.



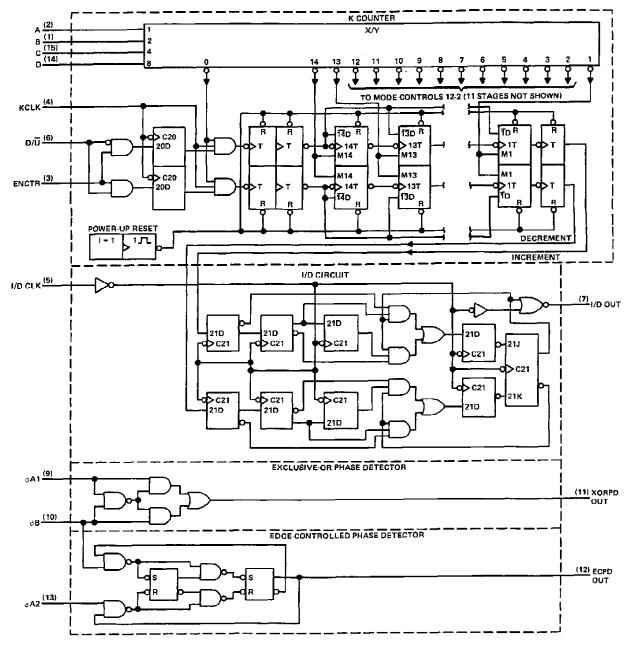
Pin numbers shown are for J, N and W packages.



#### description (continued)

The 'LS297 can perform the classic first-order phase-locked loop function without using analog components. The accuracy of the digital phase-locked loop (DPLL) is not affected by  $V_{CC}$  and temperature variations, but depends solely on accuracies of the K clock, I/D clock, and loop propagation delays. The I/D clock frequency and the divide-by-N modulos will determine the center frequency of the DPLL. The center frequency is defined by the relationship  $f_{C} = I/D$  Clock/2N (Hz).

## logic diagram (positive logic)



Pin numbers shown are for J, N, and W packages



#### K COUNTER FUNCTION TABLE (DIGITAL CONTROL)

D	С	В	Α	MODULO (K)
L	L	L	Ł	Inhibited
L	L	L	н	23
L	L	н	L	24
L L	L	Н	H	25
L	н	L	L	26
L	н	L	н	27
L	н	H H	L	28
L	Н	Н	н	29
Н	L	L	L	210
н	L	L	н	211
Н	L	н	L	212
H	L	н	Н	213
Н	Н	L	L	214
н	н	L	Н	215
н	н	Н	L	216
н	н	н	Н	217

#### **FUNCTION TABLE EXCLUSIVE OR PHASE DETECTOR**

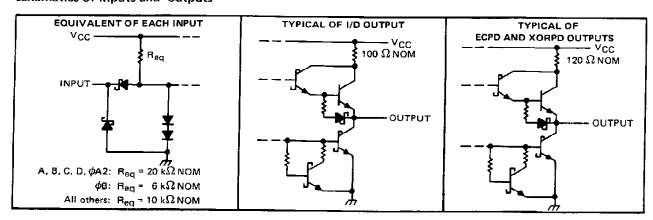
φ <b>Α</b> 1	φВ	XORPD OUT
L	L	L
L	н	н
ļн	L	н
н	н	L

**FUNCTION TABLE EDGE-CONTROLLED PHASE DETECTOR** 

<b>φA2</b>	φВ	ECPD OUT
H or L	ţ	н
Į.	HorL	L
HorL	<b>↑</b> [	No change
<b>↑</b>	HorL	No change

- H = steady-state high level
- L = steady-state low level
- = transition from high to low  $\xi$  = transition from low to high  $\xi$  = transition from low to high

### schematics of inputs and outputs



### operation

The phase detector generates an error signal waveform that, at zero phase error, is a 50% duty cycle square wave. At the limits of linear operation, the phase detector output will be either high or low all of the time, depending on the direction of the phase error  $(\phi_{in} - \phi_{Out})$ . Within these limits, the phase detector output varies linearly with the input phase error according to the gain  $k_d$ , which is expressed in terms of phase detector output per cycle of phase error. The phase detector output can be defined to vary between ±1 according to the relation:

PD Output = 
$$\frac{\% \text{ high} - \% \text{ low}}{100}$$
 (1)

The output of the phase detector will be  $k_d \phi_e$ , where the phase error  $\phi_e = \phi_{in} - \phi_{out}$ .



Exclusive-OR phase detectors (XORPD) and edge-controlled phase detectors (ECPD) are commonly used digital types. The ECPD is more complex than the XORPD logic function, but can be described generally as a circuit that changes states on one of the transitions of its inputs,  $k_d$  for an XORPD is 4 because its output remains high (PD output = 1) for a phase error of 1/4 cycle. Similarly,  $k_d$  for the ECPD is 2 since its output remains high for a phase error of 1/2 cycle. The type of phase detector will determine the zero-phase-error point, i.e., the phase separation of the phase detector inputs for  $\phi_e$  defined to be zero. For the basic DPLL system of Figure 2,  $\phi_e$  = 0 when the phase detector output is a square wave. The XORPD inputs are 1/4 cycle out of phase for zero phase error. For the ECPD,  $\phi_e$  = 0 when the inputs are 1/2 cycle out of phase.

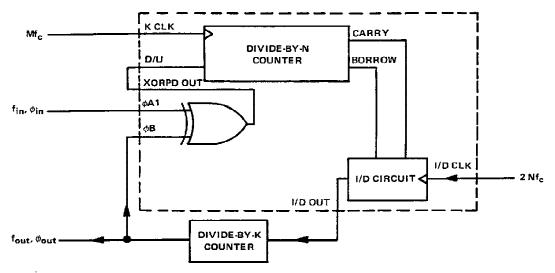


FIGURE 2-DPLL USING EXCLUSIVE OR PHASE DETECTION

The phase detector output controls the up/down input to the K counter. The counter is clocked by input frequency  $M_{C}$ , which is a multiple M of the loop center frequency  $f_{C}$ . When the K counter recycles up, it generates a carry pulse. Recycling while counting down generates a borrow pulse. If the carry and borrow outputs are conceptually combined into one output that is positive for a carry and negative for a borrow, and if the K counter is considered as a frequency divider with the ratio  $M_{C}/K$ , the output of the K counter will equal the input frequency multiplied by the division ratio. Thus the output from the K counter is  $(k_{d} \phi_{e}M_{C}^{f})/K$ .

The carry and borrow pulses go to the increment/decrement (I/D) circuit, which, in the absence of any carry or borrow pulse, has an output that is 1/2 of the input clock I/D CLK. The input clock is just a multiple, 2N, of the loop center frequency. In response to a carry or borrow pulse, the I/D circuit will either add or delete a pulse at I/D OUT. Thus the output of the I/D circuit will be Nf<sub>c</sub> + ( $k_d \phi_e Mf_c$ )/2K.

The output of the N counter (or the output of the phase-locked loop) is thus:

$$f_o = f_c + (k_d \phi_e M f_c)/2KN$$

If this result is compared to the equation for a first-order analog phase-locked loop, the digital equivalent of the gain of the VCO is just  $Mf_c/2KN$  or  $f_c/K$  for M=2N.

Thus the simple first-order phase-locked loop with an adjustable K counter is the equivalent of an analog phase-locked loop with a programmable VCO gain.



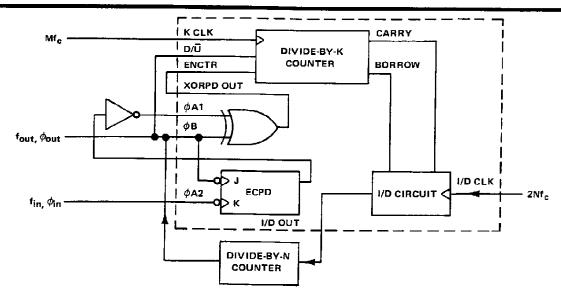


FIGURE 3-DPLL USING BOTH PHASE DETECTORS IN A RIPPLE-CANCELLATION SCHEME

# absolute maximum rating over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)	
Input voltage	
Operating free-air temperature range:	SN54LS297 – 55° C to 125° C
	SN74LS297 0°C to 70°C
Storage temperature range	······ — 65° C to 150° C

NOTE 1: Voltage values are with respect to network ground terminal,

#### recommended operating conditions

		•	SN54LS297			SN74LS297			
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
<sup>V</sup> CC	Supply voltage		4.5	5	5.5	4.75	5	5.25	V
но!	High-level output current	I/D OUT			- 1.2			- 1.2	mA
-OH		EXOR, ECPD			<b>- 400</b>			400	μА
ЮL	Low-level output current	I/D OUT			12			24	mA
	Cow-level Odtbat carrent	XOR, ECPD			4			8	mΑ
f	Clock frequency	K Clock	0		32	0		32	MHz
fclock		I/D Clock	0		16	0		16	MHz
<b>+</b>	Width of clock input pulse	K Clock	16			16			ns
t <sub>W</sub>		I/D Clock	33			33			ns
t <sub>su</sub> , to K	Setup time to K Clock t	U/D, ENCTR	30			30			пş
th	Hold time from K Clock †	U/D, ENCTR	0			0			ns
TA	Operating free-air temperature		- 55		125	0		70	°C

# SN54LS297, SN74LS297 DIGITAL PHASE-LOCKED-LOOP FILTERS

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†		SN54LS297			SN74LS297			UNIT		
			TEST CONDITIONS.			MIN	TYP#	MAX	MIN	TYP‡	MAX	UNII
VIH	High-level input v	oitage			2	-		2			V	
VIL	Low-level input v	oltage						0.7			0.8	V
Vικ	input clamp voita	ge	V <sub>CC</sub> = MIN,	I <sub>I</sub> = -18 mA				-1.5			-1.5	V
V	High-level	I/D OUT	V <sub>CC</sub> = MIN,	V <sub>IH</sub> = 2 V,	I <sub>OH</sub> = MAX	2.4			2.4			
YOH	output voltage	Others	VIL = VIL max		IOH = MAX	2.5			2.7			V
		1/D OUT			IOL = 12 mA		0.25	0.4		0.25	0.4	
1/4.	Low-level	170 301	V <sub>CC</sub> = MIN.	V <sub>IH</sub> ≈ 2 V,	IOL = 24 mA					0.35	0.5	
VOL	output voltage	Others	V <sub>IL</sub> = V <sub>IL</sub> max		IOL = 4 mA		0.25	0.4		0.25	0.4	V
		Others	,- ,-		IOL = 8 mA				_	0.35	0.5	1
l <u>į</u>	Input current at maximum input voltage		V <sub>CC</sub> = MAX,	V <sub>I</sub> ≈ 7 V			_	0.1			0,1	mΑ
	High-level	U/Ď, EN, φΑ1						40			40	
VOL o	input current	φВ	V <sub>CC</sub> = MAX, V <sub>1</sub> = 2.7 V				60			60	μА	
		All others			[			20			20	
	Low-level	U/Ď, EN, φΑ1	V <sub>CC</sub> = MAX, V <sub>J</sub> = 0.4 V					- 0.8			- 0.8	
VIL VIK VOH  VOL  II IIII III III IOS C	input current	φΒ   55		-1.2			-1.2	mA				
	input corrent	All others	V I = 0.4 V					- 0.4			- 0.4	
laa	Short-circuit	I/D OUT	V <sub>CC</sub> = MAX			-30		-130	-30		-130	mΑ
.02	output current §	Others				-20		-100	-20		-100	171,44
Icc	Supply current		V <sub>CC</sub> = MAX, All outputs open	All inputs gro	unded,		75	120		75	120	mA

<sup>†</sup>For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

# switching characteristics, VCC = 5 V, $T_A = 25^{\circ}C$

PARAMETER¶	FROM (INPUT)		FROM (INPUT) TO (OUTPUT) TEST CONI		MIN	TYP	MAX	UNIT
,	KCLK		I/D OUT		32	50		
fmax	I/D CLK		I/D OUT	RL = 667 Ω.	16	35		MH2
tPLH .	I/D CLK †		I/D OUT	CL = 45 pF, See Note 2		15	25	пs
<sup>t</sup> PHL			I/D OUT			22	35	ns
	φA1 or <b>φ</b> B	Other input low	XOR OUT			10	15	ns
<sup>t</sup> PLH	φΑ1 or φΒ	Other input high	XOR OUT			17	25	
	φA1 or φB	Other input low	XOR OUT	R <sub>L</sub> = 2kΩ,		15	25	ns
tPHL	φA1 or φB	Other input high	XOR OUT	$C_L = 45 pF$ ,		17	25	
tPLH	φВ↓		ECPD OUT	See Note 2		20	30	nş
tPHL	φA2↓		ECPD OUT			20	30	20

tpLH = propagation delay time, low-to-high-level output

 $<sup>^{\</sup>ddagger}$ All typical values are of  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}$ C.

<sup>§</sup> Not more than one output should be shorted at a time and the duration of the short-circuit should not exceed one second.

tpHL = propagation delay time, high-to-low-level output

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

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